

First time right.

The Model 1080 PicoMill® TEM specimen preparation system combines an ultra-low energy, inert gas ion source and a scanning electron column with multiple detectors to yield optimal TEM specimen preparation.

The PicoMill system is the ideal complement to focused ion beam (FIB) technology. It adds the increased capability of producing superior specimen quality while enhancing the overall specimen preparation throughput by moving final thinning offline. The ability to precisely and predictably thin a specimen reduces the potential for rework and reduces specimen processing time. This unique combination of advanced features within the PicoMill system will allow you to achieve first time right specimen preparation every time.

Fischione is with you every step of the way

To help you quickly integrate the PicoMill system into your workflow, Fischione offers excellent customer service and support. Fischione application

scientists will help you develop ion milling recipes specific to your materials, applications, and workflow. Fischione Service will install your PicoMill system and provide onsite training to your personnel.

Delivering
exceptional
customer
service



MODEL 1080

PicoMill® TEM specimen preparation system

- Achieve ultimate specimen quality — free from amorphous and implanted layers
- Complements FIB technology
- In situ imaging with ions and electrons
- Advanced detector technology for imaging and precise endpoint detection
- Microscope connectivity for risk-free specimen handling
- Adds capacity and capability
- Fast, reliable, and easy to use

